

AFRL-RQ-WP-TP-2013-0208

ADVANCED SENSOR AND PACKAGING TECHNOLOGIES FOR INTELLIGENT ADAPTIVE ENGINE CONTROLS (PREPRINT)

Michael W. Usrey, Kevin F. Harsh, and Yiping Liu Sporian Microsystems, Inc.

Alireza R. Behbahani Engine Systems Branch Turbine Engine Division

MAY 2013

Approved for public release; distribution unlimited.

See additional restrictions described on inside pages

STINFO COPY

AIR FORCE RESEARCH LABORATORY
AEROSPACE SYSTEMS DIRECTORATE
WRIGHT-PATTERSON AIR FORCE BASE, OH 45433-7542
AIR FORCE MATERIEL COMMAND
UNITED STATES AIR FORCE

NOTICE AND SIGNATURE PAGE

Using Government drawings, specifications, or other data included in this document for any purpose other than Government procurement does not in any way obligate the U.S. Government. The fact that the Government formulated or supplied the drawings, specifications, or other data does not license the holder or any other person or corporation; or convey any rights or permission to manufacture, use, or sell any patented invention that may relate to them.

This report was cleared for public release by the USAF 88th Air Base Wing (88 ABW) Public Affairs Office (PAO) and is available to the general public, including foreign nationals.

Copies may be obtained from the Defense Technical Information Center (DTIC) (http://www.dtic.mil).

AFRL-RQ-WP-TP-2013-0208 HAS BEEN REVIEWED AND IS APPROVED FOR PUBLICATION IN ACCORDANCE WITH ASSIGNED DISTRIBUTION STATEMENT.

*//Signature//

ALIREZA R. BEHBAHANI Project Manager Engine Systems Branch Turbine Engine Division //Signature//

CARLOS A. ARANA, Chief Engine Systems Branch Turbine Engine Division Aerospace Systems Directorate

This report is published in the interest of scientific and technical information exchange, and its publication does not constitute the Government's approval or disapproval of its ideas or findings.

^{*}Disseminated copies will show "//Signature//" stamped or typed above the signature blocks.

REPORT DOCUMENTATION PAGE

Form Approved OMB No. 0704-0188

The public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports (0704-0188), 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to any penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number. PLEASE DO NOT RETURN YOUR FORM TO THE ABOVE ADDRESS.

1. REPORT DATE (DD-MIM-YY)	2. REPORT TYPE		TERED (From - 10)
May 2013 Conference Paper Preprint 01 Decer			ember 2012 – 16 May 2013
4. TITLE AND SUBTITLE			5a. CONTRACT NUMBER
ADVANCED SENSOR AND PAC	KAGING TECHNOLOGIES FOR INTE	LLIGENT	FA8650-13-C-2303
ADAPTIVE ENGINE CONTROLS	S (PREPRINT)		5b. GRANT NUMBER
			5c. PROGRAM ELEMENT NUMBER
			62203F
6. AUTHOR(S)			5d. PROJECT NUMBER
Michael W. Usrey, Kevin F. Harsh,	and Yiping Liu (Sporian Microsystems,	(nc.)	3005
Alireza R. Behbahani (AFRL/RQT)	E)		5e. TASK NUMBER
			N/A
			5f. WORK UNIT NUMBER
			Q0RY
7. PERFORMING ORGANIZATION NAME(S) A	ND ADDRESS(ES)		8. PERFORMING ORGANIZATION
Sporian Microsystems, Inc. Eng.	ne Systems Branch (AFRL/RQTE)		REPORT NUMBER
	oine Engine Division		
	Force Research Laboratory, Aerospace System		
	ght-Patterson Air Force Base, OH 45433-7542		
•	Force Materiel Command, United States Air	Force	
9. SPONSORING/MONITORING AGENCY NAM	IE(S) AND ADDRESS(ES)		10. SPONSORING/MONITORING
Air Force Research Laboratory			AGENCY ACRONYM(S)
Aerospace Systems Directorate			AFRL/RQTE
Wright-Patterson Air Force Base, C	OH 45433-7542		11. SPONSORING/MONITORING
Air Force Materiel Command	AGENCY REPORT NUMBER(S)		
United States Air Force	AFRL-RQ-WP-TP-2013-0208		
12. DISTRIBUTION/AVAILABILITY STATEMEN	ІТ		

Approved for public release; distribution unlimited.

13. SUPPLEMENTARY NOTES

PA Case Number: 88ABW-2013-2324; Clearance Date: 13 May 2013. This paper contains color.

The conference paper was presented at the 59th International Instrumentation Symposium and MFPT 2013 Joint Conference, held in Cleveland, Ohio on May 13 through May 17, 2013.

14. ABSTRACT

The development of a pressure/temperature multi-sensor based on a combination of micro-electromechanical systems (MEMS) sensor technology, novel ceramic materials, high-temperature electronics, and advanced harsh-environment electronics packaging is discussed. The pressure/temperature multi-sensor enables unprecedented monitoring of propulsion, energy generation, and industrial systems. A multi-sensor approach will reduce control system weight and wiring complexity, design time, and cost. Multi-sensor control strategies do better than the single-sensor strategy on the basis of both to raise the accuracy and fault tolerance ability effectively. The resulting sensors and packaging can be manufactured at low cost and operate in corrosive environments, while measuring temperatures up to 2,552 °F (1,400 °C) with simultaneous pressure measurements up to 1,000 psi. The combination of a high-temperature, high-pressure-ratio compressor system, and adaptive engine technologies enables high thrust and efficiency.

15. SUBJECT TERMS

smart sensor, dynamic sensor, adaptive engine control, distributed engine control, HT electronics, electronics packaging

16	. SECURITY	CLASSIFICATIO	N OF:	17. LIMITATION	18. NUMBER	19a.	NAME OF RESPONSIBLE PERSON (Monitor)
		b. ABSTRACT Unclassified		OF ABSTRACT: SAR	OF PAGES 32	19b.	Alireza R. Behbahani TELEPHONE NUMBER (Include Area Code) N/A

Advanced Sensor and Packaging Technologies for Intelligent Adaptive Engine Controls

Michael W. Usrey¹, Kevin F. Harsh¹, Yiping Liu¹, Alireza R. Behbahani²

¹Sporian Microsystems, Inc., ²Air Force Research Laboratory

Keywords: Smart Sensor, Dynamic Sensor, Adaptive Engine Control, Distributed Engine Control, HT Electronics, Electronics Packaging

Abstract: The development of a pressure/temperature multi-sensor based on a combination of micro-electromechanical systems (MEMS) sensor technology, novel ceramic materials, high temperature electronics, and advanced harsh environment electronics packaging is discussed. The pressure/temperature multi-sensor enables unprecedented monitoring of propulsion, energy generation and industrial systems. Multi-sensor approach will reduce control system weight and wiring complexity, design time and cost. Multi-sensor control strategies do better than the single-sensor strategy on the basis of both to raise the accuracy and fault tolerance ability effectively. The resulting sensors and packaging can be manufactured at low cost and operate in corrosive environments, while measuring temperatures up to 2552°F (1400°C) with simultaneous pressure measurements up to 1000 psi. The combination of a high-temperature, high pressure-ratio compressor system and adaptive engine technologies enable high thrust and efficiency. The multi-sensor approach will potentially provide an opportunity for sensor level fusion where multiple sensors measuring correlated parameters. In-situ deployment of these sensors enables advanced compressor and combustor control schemes for prognostics and active control that facilitate environmentally responsible aviation. Current efforts include: combining the sensor technology with high temperature electronics to produce 'smart' sensors for distributed engine controls, capacitive transducer elements with increased dynamic bandwidth, and advanced sensor packaging technologies. The key technologies of intelligent engines are active controls, advanced diagnostics, and prognostics which require smart sensors. The ability to sense the current engine operating condition and state and react with adaptive controls requires robust sensors. It is essential that these sensors are tested in a relevance environment. In this paper, some testing will be reported. Additional engine testing is planned through the NASA Vehicle Integrated Propulsion Research (VIPR) and Air Force Small Component and Engine Structural Assessment Research (S-CAESAR) Engine Demonstrator programs.

Introduction

Former Defense Secretary Panetta linked energy and the environment to national security [1] and the Air Force is the largest consumer of fuel in the DoD [2]. Commercial airlines are also concerned with reducing fuel consumption and costs [3].

Active combustion control improves specific fuel consumption while reducing the emissions of oxides of nitrogen [4]. Dynamic pressure sensors are a key enabling technology for active combustion control, but current dynamic pressure sensors require liquid cooling to survive in situ compressor discharge (P3) temperatures which increases weight and cost [5].

As military and commercial turbine engine users have sought to increase performance and reduce costs, Distributed Engine Control (DEC) has also been identified as an important architectural paradigm shift to achieve increase flexibility, scalability, fault tolerance and performance while reducing weight, lifecycle costs and obsolescence risk [6]. 'Smart' sensors are seen as a key enabler for DEC [7].

As smart sensors, actuators and control elements are distributed around the engine, the need for robust, high temperature capable electronics and electronics packaging becomes critical [8]. While the temperature capability for electronics varies with engine location the need for a consistent communication interface does not. Therefore, the development of a communication standard for aero-engine distributed control may be constrained by the worst-case temperature condition in the engine [9]. Currently, there exists a small but increasing pool of commercial resources with capabilities for electronic components based on silicon on insulator (SOI) operable up to 300°C and multilayer of silicon carbide (SiC) electronics operable up to 500°C [10,11]. Silicon carbide's ability to function at temperatures as high as 650°C will enable large performance range enhancements for high-temperature sensor applications [12,13,14,15]. The authors have reviewed existing high-temperature electronics components and technologies and their key packaging requirements (Table 1). Based on this review, simple circuits that allow for analog sensing signal conditioning are possible, but the full suite of microprocessors. memory, DSPs, UARTs, and other digital components necessary for realization of a high temperature smart sensor are not vet available.

Table 1: HT Electronics Developers with Strong DEC Potential

Component Supplier	Passives	ICs	ASIC	Temp Range (°C)
Arkansas Power Electronics	X	X		<300
CISSIOD	X	X		<300
Cree	X	X		300-500
Honeywell	X	X	X	<300
Orbital Electronics	X	X	X	<300
Riedon	X			<400
TRS Technologies	X			<450
Vanguard Electronics	X			<250
Vectron International	X			250–300
xREL Semiconductor	X			230–300

As high temperature operable electronics become more broadly available, electronics packaging techniques suitable for the turbine engine environment must evolve as well. Specifically, the electronics packaging must be designed to endure high temperatures, large acceleration loads, and support non-planar installation [16].

In Situ Pressure Sensing

In situ, dynamic pressure sensing is critical to sensors to assess compressor surge and stall cell formation, margin, and operability; optical sensors and high temperature MEMS are emerging alternatives for these measurements [17]. Sporian Microsystems, Inc. has established a solid track record of successful research and development of high temperature sensors and packaging architectures for high temperature turbine engine and other advanced power systems environments. Sporian's sensor technology is based on the combination of advanced high temperature packaging and recently developed silicon carbide nitride (SiCN) based polymer derived ceramics (PDCs). SiCN based ceramics are a group of amorphous, high-temperature materials, which possess excellent mechanical and electric properties at temperatures up to 1800 °C, which allows for the creation of devices with much higher operational temperatures than SiC or SOI based technologies [18,19,20,21,22,23,24,25].

Figure 1 shows examples of previously developed and demonstrated SiCN temperature/pressure sensor structures and the associated packaging developed for turbine engine applications at temperatures up to 1350°C. The sensors and packaging have successfully completed 200 hours of Navy 'Iron Bird' turboshaft testing and 24 hours of OEM turbofan testing, both in the P3 position, as well as over 550 hours of OEM burner rig testing and 200 hours of DOE burner rig testing. The sensors are scheduled to be included in Air Force 'Small CAESAR' and NASA VIPR tests.



Figure 1: High Temperature, In Situ Pressure Sensors

The Sporian sensing element with the highest Technology Readiness Level (TRL) is based on a piezoresistive architecture which displays a coupled thermoresistive response. As a result, the dynamic bandwidth of the sensor is less than that specified by the Propulsion Instrumentation Working Group (PIWG) industry consortium [26]. A recent, NASA-funded effort has yielded promising results for a higher bandwidth pressure sensing architecture.

While the MEMS sensor element and packaging are relatively well developed, the associated signal conditioning and communications electronics to date are purely analog and lack many the features necessary for "smart" operation.

Smart Sensors

A smart sensor is a sensor that possesses capabilities beyond merely detecting a certain parameter and sending a raw uncompensated signal. Smart sensor functionalities can include signal conditioning, filtering, calibration, temperature compensation, linearity correction, analog-to-digital conversion, self-diagnostics, control logic, memory, and bus communication capability [27]. IEEE-1451 is a standard for a network independent connection of sensors to network controllers, including the embedding of a Transducer Electronic Data Sheet (TEDS) which allows for the connection of any transducer on the network [28].

Although network independence is a goal of IEEE-1451, data bus commonality is important to realize weight and cost reductions desired from Distributed Engine Control. Some level of commonality and standardization is also necessary to lower risk and encourage sensor and actuator vendors to enter an emerging market. Competition and economies of scale are necessary to make the new technology attractive for turbine engine manufacturers. The choice of data bus is also limited by the constraints imposed by utilization of high temperature operable electronics.

For smart sensors, firmware is a significant aspect of the operational system [29]. At present, there is an understandable lack of software/firmware development tools for emerging HT electronics. Along with the limitations of digital HT electronics, this inhibits migration of firmware developed for smart sensors utilizing traditional silicon electronics to DEC applications and drives development and support costs.

Pertinent published sources were reviewed to identify the various communications options being pursued or considered by the overall DEC community. Approximately 40 documents were reviewed, noting in detail specific communications networking technologies and standards that could be used for DEC applications. The total range included 27 different technologies or standards including various wired and wireless physical layers and higher level networking layers. For this review and list, we considered technologies that a particular document mentions as a possible option or solution, and not just the technologies that a document focuses on.

It is important to note that it is not possible to cleanly split these various technologies into categories that strictly address various networking layers. This is due to the fact that no one technology covers all required layers of a communications network. Here we use the term "layers" in the same sense as it is used in, for example, the "OSI 7 layer model" [30, 31]. Further, simply categorizing the various approaches is not strictly possible because not all communications networks can necessarily be mapped to the "OSI 7 layer model." With this said, the results of the review are presented in Table 2. The results of this review can best be summarized by saying there are a wide range of communications technologies that are potentially useful, and that are being considered for use in DEC

systems. On the positive side, a large number of qualified people are considering this question and these people appear to be giving fair consideration to all possibilities. On the negative side, no clear "winner" emerges from the published literature at this time. This means, at least from the point of view of the published literature, there is no consensus/standard/quasi-standard with respect to the communications technology to be used for DEC applications.

Table 2: Communications Technologies Addressed by Reviewed DEC Literature

Wired Interfaces	% of papers		
whed interfaces	mentioning		
RS232	12.5		
RS485	25.0		
MIL-I-1553	25.0		
ARINC	12.5		
CANbus	37.5		
MODbus	12.5		
Ethernet	25.0		
Optical Ethernet	12.5		
SAE-5652	12.5		
ARCnetPLUS	12.5		
FireWire	37.5		
SAFEBus	12.5		
FlexRay	25.0		
SPIDER	12.5		
TTP (all variants)	25.0		
J1939	12.5		
LVDS	12.5		
Wireless Interfaces			
WiFi (IEEE 802.11)	12.5		
IEEE 802.15.4	12.5		
ZigBee	12.5		
BlueTooth	12.5		
Miscellaneous			
IEEE 1451	37.5		
MicroTCA	12.5		
AMC	12.5		
VPX	12.5		
Software Defined Radio	12.5		

To supplement the literature search, the authors surveyed several relevant engine, control system, and sensor OEMs with the goal of defining:

- Preferred data bus
- Prioritized smart sensor functionality

Responses were initially solicited via email. Follow-up phone calls were made to allow for clarification and elaboration. The results of this survey are summarized in Table 3.

Table 3: Summary of Turbine Engine Supply Chain Smart Pressure Sensor Survey

Organization	Preferred Data Bus	Preferred Smart Sensor Functionality (in priority order)		
Engine OEM A	Defer to DECWG	Onboard calibration, Built-In Self-Test, TEDS		
Engine OEM B	RS-485 & Deterministic Ethernet. Comm-Over-Power	Onboard calibration, Built-In Self-Test, TEDS		
Engine OEM C	RS-485 & Deterministic Ethernet	Onboard calibration, Built-In Self-Test, TEDS		
Engine OEM D	Defer to DECWG	Defer to DECWG		
Controls OEM A	Defer to Engine OEM	Defer to Engine OEM		
Controls OEM B	Analog, Comm-Over- Power	No Sensor Bandwidth Penalty, Built-In Self-Test		
Controls OEM C ARINC 825		-		
Controls OEM D ARINC 825/CAN, Comm- Over-Power, NOT Multi- Drop Bus		Onboard calibration, Built-In Self-Test, TEDS		
Sensor OEM A	ARINC 429, Legacy Data Bus	Onboard calibration, Built-In Self-Test, TEDS		
Sensor OEM B	ARINC 429, Legacy Data Bus	Onboard calibration, Built-In Self-Test, TEDS		
Sensor OEM C ARINC 429, Legacy Data Bus		Onboard calibration, Built-In Self-Test, TEDS		

The authors also attended the DECWG Requirements Review in Cleveland on March 1, 2012. The weaknesses of several candidate data busses (lack of EMI protection, encryption for data security, licensing fees driving costs) were discussed. Though there was no apparent strong statement of endorsement, there was some apparent DECWG preference/endorsement of LIN bus and deterministic Ethernet. It was emphasized that DECWG would only support open standards to keep costs down by avoiding licensing fees. Therefore, protocols such as proprietary TTP, TTE and AFDX are apparently excluded from consideration. Since that Requirements Review meeting, the DECWG preference for LIN bus appears to have evolved to Engine Area Distributed Interconnect Network (EADIN) bus [32].

The authors' approach for dealing with the constraints of HT electronics and uncertainties of the emerging DEC application is to utilize a hybrid approach to smart sensor implementation. HT electronics would be used for critical analog signal conditioning functions such as signal amplification. Digital smart sensor functionality, such as data bus interface, built-in self-test and TEDS, would be implemented through rugged, miniaturized packaging of traditional silicon electronics for application farther away from the engine core (Figure 2).

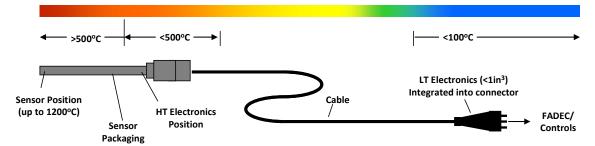


Figure 2: Smart Sensor utilizing Hybrid HT- and LT-Electronics

First generation prototypes have shown promising performance. A room temperature, digital 'smart' sensor prototype board is shown in Figure 3. This board is a 'stretch' version to allow for easy circuit debugging; the final version will be less than 1 in³.

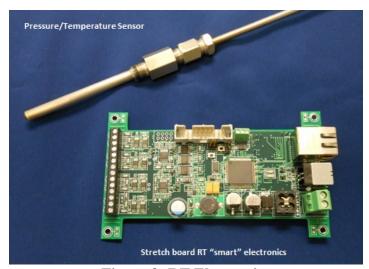


Figure 3: RT Electronics

Electronics Packaging

Traditional electronics packaging does not contemplate the elevated temperatures, acceleration loads, and constrained, non-planar application of a DEC environment. Therefore, an adaptable, conformal, high-temperature packaging and installation methodology is needed to support emerging high temperature electronics technology [33,34,35].

The key issue is that, as these components leverage typical planar wafer fabrication process flows, the resulting components are in discrete "chip" or "die" formats that cannot be realized in a non-planar form and cannot be applied to conformal surfaces without additional packaging [36,37,38]. Further, as these new high temperature processes are vastly less advanced than traditional semiconductor processes, currently only functionally simple elements (MOSFETs, diodes, SSI) have been realized. As a result, differing processes are often required to realize different components, which means combining such components into basic sensing and signal conditioning circuits typically requires multi-chip (discrete component) packaging integration. Such multi-chip module packaging for ultra-high temperature electronics is a relatively unexplored area,

and conformally interfacing such approaches with non-planar engine components is an even more novel problem.

The technical approach for this effort has been to utilize proven packaging technologies combined with new high temperature materials to create conformal multi-component modules and realize a generic and adaptable packaging methodology that can be applied to non-planar aerospace structures. The first step is a specially fabricated, non-planar substrate. The substrate is patterned with metallization to form both electrical interconnects, routing and potentially transmitter components including low profile antennae, resistors and/or capacitors. Electronic components would be attached to this substrate via either flip-chip bonding or high temperature die attach and necessary additional interconnects formed using high temperature wire or ribbon bonding. The discrete components and substrate would then be coated or encapsulated with an electrically insulating layer to protect the electronics from the harsh environment and increase the overall durability, with the exception of any portions (e.g. pressure sensing elements) that may require exposure to the environment. This "conformal package" would be bonded to the target location via a ductile intermediate layer.

Each step in this packaging process is being systematically developed by the authors to yield a packaging methodology that meets or exceeds the environmental constraints of current HT electronics components. Results from this effort are summarized in Table 4.

Conclusions

Continuing improvements in turbine engine performance will require a technology convergence of high temperature sensing, high temperature electronics, high temperature packaging, and advanced control systems.

Acknowledgements

This material is based upon work supported by the US Air Force under Contract Numbers FA8650-12-M-2212 and FA8650-12-M-2219. Any opinions, findings and conclusions or recommendations expressed in this material are those of the author(s) and do not necessarily reflect the views of the US Air Force.

Table 4: Packaging Process Development

Test Item T (°C) Duration/G Results 5-type ceramic substrate 600°C 100hr, multicycle No degradation on flexural strength, Dimensionally stable 5-type ceramic substrate 850°C Single sweep Low dielectric dissipation under 500°C Conformal Au metallization 600°C 100hr, multicycle Reliable electrical continuity, and adhesion Multilayer conformal substrate 600°C 100hr, multicycle Good geometrical and dimensional stability Multilayer Au metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer Pt metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer With via/window 600°C 100hr, multicycle Reliable electrical continuity and adhesion Die-attach 600°C 100hr, multicycle Reliable electrical continuity and adhesion Au wire bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, and adhesion Au Wire bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Reliable electrical continuity, Reliable electrical continuity, Reliable electrical con	1a	ble 4: Pac	Development		
5-type ceramic substrate 850°C Single sweep Low dielectric dissipation under 500°C Conformal Au metallization 600°C 100hr, multicycle Reliable electrical continuity, and adhesion Multilayer conformal 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer conformal 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer Protection of 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer Protection of 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer Protection of 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer Protection of 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer With via/window 600°C 100hr, multicycle Reliable electrical continuity and adhesion Die-attach cements 1000°C 20hr, Multicycle Shear strength can survive 56 kG 100hr, multicycle Reliable electrical continuity, and adhesion 100hr, multicycle Shear strength and survive 56 kG 100hr, multicycle Reliable electrical continuity, metallization 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Reliable electrical continuity, Reliable electrical continuity, Reliable mechanical attachment 1000°C 100hr, multicycle Reliable electrical continuity, Reliable mechanical attachment 1000°C 20hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Reliable electrical continuity, Reliable rechanical attachment 1000°C 100hr, multicycle No degradation of performance 100hr No degradation of performance 100hr No degradation 10 performance 100hr No degradation 10 performance 100hr, multicycle No degradation 10 performance 100hr	Test Item	T (°C)	Duration/G	Results	
Stype ceramic substrate	E tumo como mio cultotrato	coosc	100hr multiquele	No degradation on flexural strength,	
Conformal Au metallization 600°C 100hr, multicycle Reliable electrical continuity, and adhesion 600°C 100hr, multicycle 3 door geometrical and dimensional stability 100hr, multicycle 100hr, mu	5-type cerainic substrate	800 C	100m, multicycle	Dimensionally stable	
Conformal Pt metallization	5-type ceramic substrate	850°C	Single sweep	Low dielectric dissipation under 500°C	
Multilayer conformal substrate 600°C 100hr, multicycle stability Good geometrical and dimensional stability stability Multilayer Au metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer Pt metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer with via/window 600°C 100hr, multicycle Reliable electrical continuity and adhesion Die-attach 600°C 100hr, multicycle No degradation on shear strength Au wire bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, limited deformation/softening Au flip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Reliable pleactrical continuity, Reliable pleactrical continuity, Reliable pleactrical continuity, Reliable pleactrical continuity Potting cements 1000°C 220hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle Reliable electrical continuity Potting cements 600°C 100hr, nulticycle No degradation of performance Potting cements 600°C 100hr, multicycle	Conformal Au metallization	600°C	100hr, multicycle	Reliable electrical continuity, and adhesion	
Substrate 600°C 100hr, multicycle stability Multilayer Au metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer With via/window 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer with via/window 600°C 100hr, multicycle Shear strength can survive 56 kG Die-attach cements 600°C 100hr, multicycle Reliable electrical continuity and adhesion Au wire bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, Limited deformation/softening Au flip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable mechanical attachment Potting cements 600°C 100hr, multicycle Reliable electrical continuity, Reliable mechanical attachment Potting cements 600°C 100hr, multicycle No degradation of performance Pottotype w/ potting 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ coating 600°C 100hr, multicycle <td>Conformal Pt metallization</td> <td>600°C</td> <td>100hr, multicycle</td> <td>Reliable electrical continuity and adhesion</td>	Conformal Pt metallization	600°C	100hr, multicycle	Reliable electrical continuity and adhesion	
substrate stability Multilayer Au metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer Pt metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer with via/window 600°C 100hr, multicycle Reliable electrical continuity and adhesion Die-attach cements 1000°C 100hr, multicycle No degradation on shear strength Au wire bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, limited deformation/softening Au wire bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, nulticycle Multip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Reliable electrical continuity, Reliable electrical continuity Potting cements 1000°C >20hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle No degradation of performance Potting cements 600°C 1		600°C	100hr. multicycle		
Multilayer Pt metallization 600°C 100hr, multicycle Reliable electrical continuity and adhesion Multilayer with via/window 600°C 100hr, multicycle Reliable electrical continuity and adhesion Die-attach cements 600°C 100hr, multicycle Shear strength can survive 56 kG Die-attach 600°C 100hr, multicycle No degradation on shear strength Au wire bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, Limited deformation/softening Au flip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Eliable mechanical attachment Au flip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Limited deformation/softening Potting cements 1000°C 220hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ coating 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ coating <td></td> <td></td> <td><u> </u></td> <td>,</td>			<u> </u>	,	
Multilayer with via/window 600°C 100hr, multicycle Reliable electrical continuity and adhesion Die-attach cements 1000°C >20hr, Multicycle Shear strength can survive 56 kG Die-attach 600°C 100hr, multicycle No degradation on shear strength Au wire bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, Limited deformation/softening Au flip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Elimited deformation/softening Au flip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Limited deformation/softening Potting cements 1000°C 100hr, multicycle Reliable electrical continuity, Reliable mechanical attachment Potting cements 1000°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity Prototype w/ coating 6					
Die-attach cements 1000°C >20hr, Multicycle Shear strength can survive 56 kG Die-attach 600°C 100hr, multicycle No degradation on shear strength Au wire bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, milticycle in the deformation/softening Au flip-chip bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable mechanical attachment Au wire bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Reliable mechanical attachment Potting cements 1000°C >20hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity Installation: Au-paste 600°C 100hr, multicycle No degradation on materials Prototype w/ coating 600°C 100hr, multicycle Die shear samples survived 30 kG Installation: Au-paste 600°C				, , , , , , , , , , , , , , , , , , ,	
Die-attach Au wire bonding on Au metallization Au flip-chip bonding on Au metallization Au wire bonding on Au flip-chip bonding on Au metallization Au wire bonding on Pt metallization Au flip-chip Boo°C 100hr, multicycle Aliable electrical continuity, Reliable electrical continuity Reliable electrical continuity Au degradation of performance Die shear strength can survive 56 kG Prototype w/ potting Goo°C 100hr, multicycle Au degradation on materials Au flip-chip Boo°C 100hr, multicycle Die shear samples survived 30 kG Installation: Au-paste Goo°C 100hr, multicycle Die shear samples survived 30 kG Installis M-M Brazing Boo°C 100hr, multicycle Die shear samples survived 30 kG Bonding/installation Au-paste and brazing joints survived Bonding/installation 300°C 1.3 kG Au-paste and brazing joints survived Bonding/installation 500°C 1.4 kG Reliable electrical continuity Beliable electrical continuity Bel	Multilayer with via/window	600°C		Reliable electrical continuity and adhesion	
Au wire bonding on Au metallization Au flip-chip bonding on Au metallization Au flip-chip bonding on Au metallization Au wire bonding on Pt metallization Au wire bonding on Pt metallization Au wire bonding on Pt metallization Au flip-chip bonding on Pt metallization Footting cements Foot'C 100hr, multicycle Foottype w/ potting Foottype w/ coating Foot'C 100hr, multicycle Foottype w/ coating Foot'C 100hr, multicycle Foots packaging foot'C 100hr, multicycle Foots packaging/insts survived Foots packaging/insts survived Foots packaging/insts survived Foots packaging/installation Foottype w/ soot packaging/installation Foottype poottypes Foot'C 100 hr, multicycle Foots packaging/installation Foottype poottypes Foottype pockaging Foottyp	Die-attach cements	1000°C	•	Shear strength can survive 56 kG	
metallization Limited deformation/softening Au flip-chip bonding on Au metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable mechanical attachment Au wire bonding on Pt metallization 600°C 100hr, multicycle Imited deformation/softening Au flip-chip bonding on Pt metallization 600°C 100hr, multicycle Reliable electrical continuity, Reliable mechanical attachment Potting cements 1000°C >20hr, multicycle No degradation of performance Potting cements 600°C 100hr, 10-cycle Reliable electrical continuity Prototype w/ potting 600°C 100hr, 10-cycle Reliable electrical continuity Thermal spray coat 700°C 30min Reliable electrical continuity and adhesion Coating glazes 600°C 100hr, multicycle No degradation on materials Prototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity Installation: Cements 600°C 100hr, multicycle Die shear samples survived 30 kG Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 30 kG Bonding/installation 80		600°C		No degradation on shear strength	
Au flip-chip bonding on Au metallization Au wire bonding on Pt metallization Au wire bonding on Pt metallization Au flip-chip bonding on Pt metallization Potting cements 1000°C 20hr, multicycle Potting cements 600°C 100hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, multicycle Reliable electrical continuity Reliab		600°C	100hr, multicycle	• •	
metallizationReliable mechanical attachmentAu wire bonding on Pt metallization600°C100hr, multicycleReliable electrical continuity, Limited deformation/softeningAu flip-chip bonding on Pt metallization600°C100hr, multicycleReliable electrical continuity, Reliable electrical continuity, Reliable mechanical attachmentPotting cements1000°C>20hr, multicycleNo degradation of performancePotting cements600°C100hr, multicycleShear strength can survive 56 kGPrototype w/ potting600°C100hr, multicycleReliable electrical continuityThermal spray coat700°C30minReliable electrical continuity and adhesionCoating glazes600°C100hr, multicycleNo degradation on materialsPrototype w/ coating600°C100hr, multicycleDie shear samples survived 30 kGInstallation: Cements600°C100hr, multicycleDie shear samples survived 30 kGInstallation: Au-paste600°C100hr, multicycleDie shear samples survived 30 kGInstall: C-M Brazing600°C100hr, multicycleDie shear samples survived 30 kGInstall: M-M Brazing800°C100hr, multicycleDie shear samples survived 900 kGBonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation800°C1.3 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypes600°C1.3 kGReliable electroni				Limited deformation/softening	
Au wire bonding on Pt metallization Au flip-chip bonding on Pt metallization Au flip-chip bonding on Pt metallization Boo°C 100hr, multicycle 100hr, multicycle Reliable electrical continuity, Reliable electrical continuity, Reliable mechanical attachment Potting cements 1000°C 20hr, multicycle Potting cements 600°C 100hr, multicycle Prototype w/ potting 600°C 100hr, multicycle Prototype w/ potting 600°C 100hr, multicycle Reliable electrical continuity Reliable electrical continuity Reliable electrical continuity Reliable electrical continuity and adhesion Reliable electrical continuity and adhesion Reliable electrical continuity and adhesion Reliable electrical continuity Reliable electrical continuity and adhesion Reliable electrical continuity and adhesion Rooning glazes Frototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity R	Au flip-chip bonding on Au	600°C	100hr, multicycle	Reliable electrical continuity,	
metallizationLimited deformation/softeningAu flip-chip bonding on Pt metallization600°C100hr, multicycleReliable electrical continuity, Reliable mechanical attachmentPotting cements1000°C>20hr, multicycleNo degradation of performancePotting cements600°C100hr, multicycleShear strength can survive 56 kGPrototype w/ potting600°C100hr, 10-cycleReliable electrical continuityThermal spray coat700°C30minReliable electrical continuity and adhesionCoating glazes600°C100hr, multicycleNo degradation on materialsPrototype w/ coating600°C100hr, multicycleNo degradation on materialsPrototype w/ coating600°C100hr, multicycleDie shear samples survived 30 kGInstallation: Au-paste600°C100hr, multicycleDie shear samples survived 30 kGInstall: C-M Brazing600°C100hr, multicycleDie shear samples survived 30 kGInstall: M-M Brazing800°C100hr, multicycleDie shear samples survived 900 kGBonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypes600°C1 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationDie-attach800°C100 hr, multicycleNo appa	metallization			Reliable mechanical attachment	
Au flip-chip bonding on Pt metallization Potting cements 1000°C 20hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, 10-cycle Reliable electrical continuity Thermal spray coat 700°C 30min Reliable electrical continuity Thermal spray coat 700°C 100hr, multicycle Prototype w/ coating 600°C 100hr, multicycle Installation: Cements 600°C 100hr, multicycle Installation: Au-paste 600°C 100hr, multicycle Installation: Au-paste 600°C 100hr, multicycle Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 30 kG Installi M-M Brazing 800°C 100hr, multicycle Die shear samples survived Au-paste and brazing joints survived 80nding/installation 800°C 100hr, multicycle No apparent degradation	Au wire bonding on Pt	600°C	100hr, multicycle	Reliable electrical continuity,	
metallization Potting cements 1000°C >20hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, 10-cycle Reliable electrical continuity Thermal spray coat 700°C 30min Reliable electrical continuity and adhesion Coating glazes 600°C 100hr, multicycle No degradation on materials Prototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity Installation: Cements 600°C 100hr, multicycle Die shear samples survived 30 kG Installation: Au-paste 600°C 100hr, multicycle Die shear samples survived 30 kG Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 30 kG Installi M-M Brazing 800°C 100hr, multicycle Die shear samples survived 900 kG Au-paste and brazing joints survived Bonding/installation 800°C 1.3 kG Au-paste and brazing joints survived Au-paste and brazing joints survived Complete prototypes Room 17 kG Reliable electronics packaging/installation Complete prototypes 600°C 1 kG Reliable electronics packaging/installation Netallization 800°C 100 hr, multicycle No apparent degradation Die-attach 800°C 100 hr, multicycle Survived Substrate materials 800°C 100 hr, multicycle Decreased strength Prototype packaging 300°C 13 kG Reliable high-T high-G performance	metallization			Limited deformation/softening	
metallization Reliable mechanical attachment Potting cements 1000°C >20hr, multicycle No degradation of performance Potting cements 600°C 100hr, multicycle Shear strength can survive 56 kG Prototype w/ potting 600°C 100hr, nulticycle Reliable electrical continuity Thermal spray coat 700°C 30min Reliable electrical continuity and adhesion Coating glazes 600°C 100hr, multicycle No degradation on materials Prototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity Installation: Cements 600°C 100hr, multicycle Die shear samples survived 30 kG Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 56 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 900 kG Bonding/installation Room 8.3 kG Au-paste and brazing joints survived Bonding/installation 300°C 4.6 kG Au-paste and brazing joints survived Bonding/installation 500°C 1.3 kG Reliable electronics packaging/installation	Au flip-chip bonding on Pt	600°C	100hr multicyclo	Reliable electrical continuity,	
Potting cements600°C100hr, multicycleShear strength can survive 56 kGPrototype w/ potting600°C100hr, 10-cycleReliable electrical continuityThermal spray coat700°C30minReliable electrical continuity and adhesionCoating glazes600°C100hr, multicycleNo degradation on materialsPrototype w/ coating600°C100hr, multicycleReliable electrical continuityInstallation: Cements600°C100hr, multicycleDie shear samples survived 30 kGInstallation: Au-paste600°C100hr, multicycleDie shear samples survived 56 kGInstall: M-M Brazing600°C100hr, multicycleDie shear samples survived 30 kGInstall: M-M Brazing800°C100hr, multicycleDie shear samples survived 900 kGBonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototy	metallization	000 C	100m, municycle	Reliable mechanical attachment	
Prototype w/ potting600°C100hr, 10-cycleReliable electrical continuityThermal spray coat700°C30minReliable electrical continuity and adhesionCoating glazes600°C100hr, multicycleNo degradation on materialsPrototype w/ coating600°C100hr, multicycleReliable electrical continuityInstallation: Cements600°C100hr, multicycleDie shear samples survived 30 kGInstallation: Au-paste600°C100hr, multicycleDie shear samples survived 56 kGInstall: C-M Brazing800°C100hr, multicycleDie shear samples survived 30 kGInstall: M-M Brazing800°C100hr, multicycleDie shear samples survived 900 kGBonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Potting cements	1000°C	>20hr, multicycle	No degradation of performance	
Thermal spray coat 700°C 30min Reliable electrical continuity and adhesion Coating glazes 600°C 100hr, multicycle No degradation on materials Prototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity Installation: Cements 600°C 100hr, multicycle Die shear samples survived 30 kG Installation: Au-paste 600°C 100hr, multicycle Die shear samples survived 56 kG Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 900 kG Bonding/installation Room 8.3 kG Au-paste and brazing joints survived Bonding/installation 300°C 4.6 kG Au-paste and brazing joints survived Bonding/installation 500°C 1.3 kG Au-paste and brazing joints survived Complete prototypes Room 17 kG Reliable electronics packaging/installation Complete prototypes 600°C 1 kG Reliable electronics packaging/installation Die-attach 800°C 100 hr, multicycle No apparent degradation Wire bond, flip-chip 800°C 100 hr, multicycle Survived Sustrate materials 800°C 100 hr, multicycle Decreased strength Prototype packaging 300°C 13 kG Reliable high-T high-G performance	Potting cements	600°C	100hr, multicycle	Shear strength can survive 56 kG	
Coating glazes 600°C 100hr, multicycle Reliable electrical continuity Installation: Cements 600°C 100hr, multicycle Die shear samples survived 30 kG Installation: Au-paste 600°C 100hr, multicycle Die shear samples survived 56 kG Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 900 kG Bonding/installation Room 8.3 kG Au-paste and brazing joints survived Bonding/installation 300°C 4.6 kG Au-paste and brazing joints survived Bonding/installation 500°C 1.3 kG Au-paste and brazing joints survived Complete prototypes Room 17 kG Reliable electronics packaging/installation Complete prototypes 600°C 1 kG Reliable electronics packaging/installation Metallization 800°C 100 hr, multicycle No apparent degradation Die-attach 800°C 100 hr, multicycle Survived Substrate materials 800°C 100 hr, multicycle Decreased strength Prototype packaging 300°C 13 kG Reliable high-T high-G performance	Prototype w/ potting	600°C	100hr, 10-cycle	Reliable electrical continuity	
Prototype w/ coating 600°C 100hr, multicycle Reliable electrical continuity Installation: Cements 600°C 100hr, multicycle Die shear samples survived 30 kG Installation: Au-paste 600°C 100hr, multicycle Die shear samples survived 56 kG Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 900 kG Bonding/installation Room 8.3 kG Au-paste and brazing joints survived Bonding/installation 300°C 4.6 kG Au-paste and brazing joints survived Bonding/installation 500°C 1.3 kG Au-paste and brazing joints survived Complete prototypes Room 17 kG Reliable electronics packaging/installation Complete prototypes 600°C 1 kG Reliable electronics packaging/installation Metallization 800°C 100 hr, multicycle No apparent degradation Die-attach 800°C 100 hr, multicycle Survived Substrate materials 800°C 100 hr, multicycle Decreased strength Prototype packaging 300°C 13 kG Reliable high-T high-G performance	Thermal spray coat	700°C	30min	Reliable electrical continuity and adhesion	
Installation: Cements600°C100hr, multicycleDie shear samples survived 30 kGInstallation: Au-paste600°C100hr, multicycleDie shear samples survived 56 kGInstall: C-M Brazing600°C100hr, multicycleDie shear samples survived 30 kGInstall: M-M Brazing800°C100hr, multicycleDie shear samples survived 900 kGBonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Coating glazes	600°C	100hr, multicycle	No degradation on materials	
Installation: Au-paste 600°C 100hr, multicycle Die shear samples survived 56 kG Install: C-M Brazing 600°C 100hr, multicycle Die shear samples survived 30 kG Install: M-M Brazing 800°C 100hr, multicycle Die shear samples survived 900 kG Bonding/installation Room 8.3 kG Au-paste and brazing joints survived Bonding/installation 300°C 4.6 kG Au-paste and brazing joints survived Bonding/installation 500°C 1.3 kG Au-paste and brazing joints survived Complete prototypes Room 17 kG Reliable electronics packaging/installation Complete prototypes 600°C 1 kG Reliable electronics packaging/installation Metallization 800°C 100 hr, multicycle No apparent degradation Die-attach 800°C 100 hr, multicycle Survived Substrate materials 800°C 100 hr, multicycle Decreased strength Prototype packaging 300°C 13 kG Reliable high-T high-G performance	Prototype w/ coating	600°C	100hr, multicycle	Reliable electrical continuity	
Install: C-M Brazing600°C100hr, multicycleDie shear samples survived 30 kGInstall: M-M Brazing800°C100hr, multicycleDie shear samples survived 900 kGBonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Installation: Cements	600°C	100hr, multicycle	Die shear samples survived 30 kG	
Install: M-M Brazing800°C100hr, multicycleDie shear samples survived 900 kGBonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Installation: Au-paste	600°C	100hr, multicycle	Die shear samples survived 56 kG	
Bonding/installationRoom8.3 kGAu-paste and brazing joints survivedBonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Install: C-M Brazing	600°C	100hr, multicycle	Die shear samples survived 30 kG	
Bonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Install: M-M Brazing	800°C	100hr, multicycle	Die shear samples survived 900 kG	
Bonding/installation300°C4.6 kGAu-paste and brazing joints survivedBonding/installation500°C1.3 kGAu-paste and brazing joints survivedComplete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Bonding/installation	Room	8.3 kG	Au-paste and brazing joints survived	
Complete prototypesRoom17 kGReliable electronics packaging/installationComplete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Bonding/installation	300°C	4.6 kG		
Complete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Bonding/installation	500°C	1.3 kG	Au-paste and brazing joints survived	
Complete prototypes600°C1 kGReliable electronics packaging/installationMetallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance		Room	17 kG		
Metallization800°C100 hr, multicycleNo apparent degradationDie-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance		600°C	1 kG		
Die-attach800°C100 hr, multicycleNo apparent degradationWire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance		800°C	100 hr, multicycle		
Wire bond, flip-chip800°C100 hr, multicycleSurvivedSubstrate materials800°C100 hr, multicycleDecreased strengthPrototype packaging300°C13 kGReliable high-T high-G performance	Die-attach				
Substrate materials 800°C 100 hr, multicycle Decreased strength Prototype packaging 300°C 13 kG Reliable high-T high-G performance					
Prototype packaging 300°C 13 kG Reliable high-T high-G performance				Decreased strength	
			· · · · · · · · · · · · · · · · · · ·		
			-		

References

[1] N Simeone, "Panetta: Environment Emerges as National Security Concern." http://www.defense.gov/news/newsarticle.aspx?id=116192, *American Forces Press Service*, May 3, 2012.

[3] A Delmar-Morgan, "Fuel Costs Slam Profit at Emirates Airline," *The Wall Street Journal*, May 10, 2012.

^[2] D Gillet, "Perspective on Propulsion Safety Affordability & Readiness." *The 2011 Propulsion Safety Affordability and Readiness (P-SAR) Conference*, Jacksonville, Florida, March 15, 2011.

- [4] JC DeLaat, KJ Breisacher, JR Saus, and DE Paxson, "Active Combustion Control for Aircraft Gas Turbine Engines." *36th Joint Propulsion Conference and Exposition*, Huntsville, Alabama, July 17-19, 2000. NASA TM 2000-210346, AIAA –2000-3500.
- [5] RS Okojie, JC DeLaat, and JR Saus, "SiC Pressure Sensor for Detection of Combustor Thermo-Acoustic Instabilities." *13th International Conference on Solid-State Sensors, Actuators and Microsystems*, Seoul, Korea, June 5-9, 2005. Volume 1, p. 470-473.
- [6] A Behbahani, D Cully, B Smith, C Darouse, R Millar, B Wood, J Krodel, S Carpenter, B Mailander, T Mahoney, R Quinn, C Bluish, B Hegwood, G Battestin, W Roney, W Rhoden, B Storey, "Status, Vision, and Challenges of an Intelligent Distributed Engine Control Architecture," *Proceedings of the 2007 SAE Aero Tech Congress & Exhibition*, July 2007.
- [7] JA DeCastro, T Liang, CS Byington, DE Culley, "Analysis of Decentralization and Fault-Tolerance Concepts for Distributed Engine Control," 45th AIAA/ASME/SAE/ASEE Joint Propulsion Conference & Exhibit, August 2009.
- [8] A Behbahani, B Wood, D Benson, A Berner, B Hegwood, J Dejager, W Rhoden, B Ohme, J Sloat, C Harmon, "Technology Requirements and Development for Affordable High-Temperature Distributed Engine Controls," 58th International Instrumentation Symposium, June 2012.
- [9] DE Culley, R Thomas, J Saus, "Concepts for Distributed Engine Control," 43rd AIAA/ASME/SAE/ASEE Joint Propulsion Conference & Exhibit, July 2007.
- [10] PG Neudeck, RS Okojie, LY Chen, "High-Temperature Electronics—A Role for WideBandgap Semiconductors?" *Proceedings of the IEEE*, vol. 90, no. 6, pp. 1065–1076, 2002.
- [11] PG Neudeck, DJ Spry, LY Chen, et al., "6H-SiC Transistor Integrated Circuits Demonstrating Prolonged Operation at 500 C," *IMAPS International Conference and Exhibition on High Temperature Electronics (HiTEC 2008)*, May 12–15, 2008, Albuquerque, New Mexico.
- [12] AB Lostetter, KJ Olejniczak and AA Elshabini, "Silicon-Carbide Power Die Packaging in Diamond Substrate Multichip Power Module Applications", 2001 *IMAPS Conference*, Baltimore, Maryland.
- [13] AB Lostetter, KJ Olejniczak, W Brown and AA Elshabini, "The Utilization of Diamond and Diamond-Like Carbon Substrates for High-Performance Power Electronic Packaging Applications", 2001 Euro. Power Elec. Conference, Austria.
- [14] CL Tan, M Habib and FD Barlow, "Electrical and Mechanical Evaluation of Thermal Spray Coatings for High Power & High Tempertaure Modules", in preparation.
- [15] MA Huque1, LM Tolbert, BJ Blalock, SK Islam, "Silicon-on-insulator-based high-voltage, high-temperature integrated circuit gate driver for silicon carbide-based power field effect transistors," *IET Power Electron.*, 2010, Vol. 3, Iss. 6, pp. 1001–1009.
- [16] "Conformal Packaging and Installation Techniques for In Situ Sensors In Extreme Environments," SBIR Topic AF112-165.

- [17] "Gas Turbine Engine Test Cell Instrumentation," RTO-AVT-180, Draft as of 10/16/2012.
- [18] E Kroke, YL Li, C Konetschny, E Lecomte, C Fasel and R Riedel, "Silazane Derived Ceramics and Related Materials," *Mat. Sci. Eng.*: R, 26, 97-199 (2000).
- [19] R Riedel, G Passing, H Schonfelder and RJ Brook, "Synthesis of Dense Silicon-Based Ceramics at Low-Temperatures," *Nature*, 35, 714-716 (1992).
- [20] R Riedel, A Kienzle, W Dressler, L Ruwisch, J Bill and F Aldinger, "A Silicoboron Carbonotride Ceramics Stable to 2000 Degrees C," *Nature*, 382, 796-798 (1996).
- [21] M Weinmann, J Schuhmacher, JQ Peng, HJ Seifert, M Christ, K Muller, J Bill, F Aldinger, "Synthesis and thermal behavior of novel Si-B-C-N ceramic precursors", *Chemistry of Materials*, Vol 12 (3), 623-632 (2000)
- [22] G Pouskouleli, "Metallorganic Compounds as Preceramic Materials, I. Non-Oxide Ceramics," *Ceram. Int.*, 15, 1989.
- [23] M Peuckert, T Vahs and M Brueck, "Ceramic From Organometallic Polymers," *Advanced Materials*, 2, 398 (1990).
- [24] R Raj, L An, S Shah, R Riedel, C Fasel and HJ Kleebe, "Oxidation Kinetics of An Amorphous Silicon Carbonitride Ceramics," J. Am. Ceram. Soc., 84 (8), 1803-1810 (2001).
- [25] E Butchereit, KG Nickel and A Muller, "Precursor-Derived Si-B-C-N ceramics: Oxidation Kinetics," *J. Am. Ceram. Soc.*, 84[10], 2184-2188 (2001).
- [26] http://www.piwg.org/sensor/sensor hdpressure.html.
- [27] "Top Technologies in Sensors and Controls Cluster," Frost & Sullivan, June 2012.
- [28] KC Lee, MH Kim, S Lee, HH Lee, "IEEE-1451-based Smart Module for In-vehicle Networking Systems of Intelligent Vehicles," *IEEE Transactions on Industrial Electronics*, Volume 51, Issue 6, Dec. 2004 Pages: 1150 1158.
- [29] D Culley, "Transition in Gas Turbine Control System Architecture: Modular, Distributed, and Embedded," *Turbo Expo 2010*, June 2010.
- [30] ISO/IEC, "Information Technology Open Systems Interconnection Basic Reference Model: The Basic Model," *International Standard 7498-1*, 2nd Edition corrected and Reprinted June 15, 1996.
- [31] H Zimmerman, "OS1 Reference Model-The IS0 Model of Architecture for Open Systems Interconnection", *IEEE Transaction on Communications*, Vol. COM-28, No. 4, April 1980.
- [32] A Berner, "Engine Area Distributed Interconnect Network EADIN a DECWG Proposed Serial Communication Bus for SAE Consideration," SAE 2012 Aerospace Electronics and Avionics Systems Conference, October 2012.
- [33] LY Chen, RS Okojie, PG Neudeck, GW and Hunter, "Material System for Packaging 500°C MicroSystems," MRS Proc., Symposium N: Microelectronic, Optoelectronic, and MEMS Packaging, CA, 2001.
- [34] LY Chen, GW Hunter, and PG Neudeck, "Silicon Carbide Die Attach Scheme for 500°C Operation," MRS 2000 Spring Meeting Proceedings-Wide-Bandgap Electronic Devices Symposium, San Francisco, CA, April 10–14, 2000.
- [35] RR Gryzbowski, M Gericke, M., "500°C Electronics Packaging and Test Fixturing", Second International High Temperature Electronics Conference, Charlotte, NC, June, 1994.

- [36] AB Lostetter, KJ Olejniczak and AA Elshabini, "Silicon-Carbide Power Die Packaging in Diamond Substrate Multichip Power Module Applications", 2001 IMAPS Conference, Baltimore, Maryland, 2001.
- [37] AB Lostetter, KJ Olejniczak, W Brown and AA Elshabini, "The Utilization of Diamond and Diamond-Like Carbon Substrates for High-Performance Power Electronic Packaging Applications", 2001 Euro. Power Elec. Conference, Austria, 2001.
- [38] CL Tan, M Habib and FD Barlow, "Electrical and Mechanical Evaluation of Thermal Spray Coatings for High Power & High Tempertaure Modules", in preparation.



Setting the Standard for Automation™

16 May 2013

Instrumentation - Aerospace Applications
Intelligent Turbine Engine Controls
Session E4 - Roxy



Advanced Sensor and Packaging Technologies for Intelligent Adaptive Engine Controls

Michael W. Usrey¹,

Kevin F. Harsh¹, Yiping Liu¹, Alireza R. Behbahani²
¹Sporian Microsystems, Inc., ²Air Force Research Laboratory

Standards

Certification

Education & Training

Publishing

Conferences & Exhibits

59th International Instrumentation, Symposium – Cleveland, OH

Presenter



Mike Usrey

- Vice President at Sporian Microsystems, Inc.
- Ph.D. Industrial Engineering-University of Minnesota
- Professional Engineer / Certified in Production & Inventory Mgmt
- Previously:
 - Project Manager Honeywell
 - CTO EnergyWindow
 - CEO Protocol Communications
 - Faculty University of Colorado



Outline



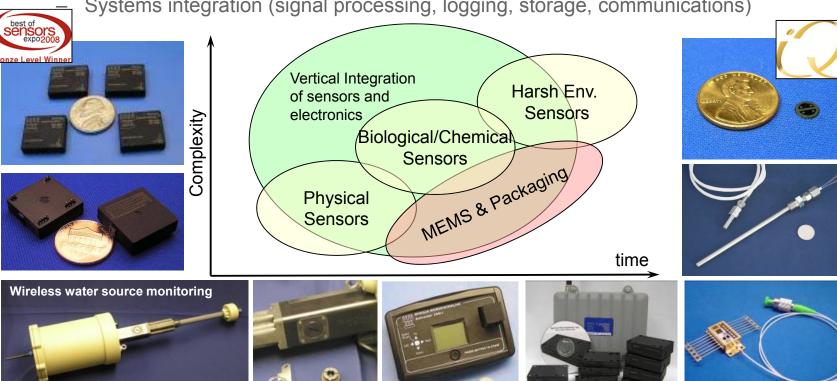
- About Sporian
- Motivation
- Smart Pressure Sensor Concept
- Analog Pressure Sensor
- High Temperature Electronics
- High Temperature, Conformal Packaging
- Results to Date

About Sporian



4 primary development efforts at Sporian:

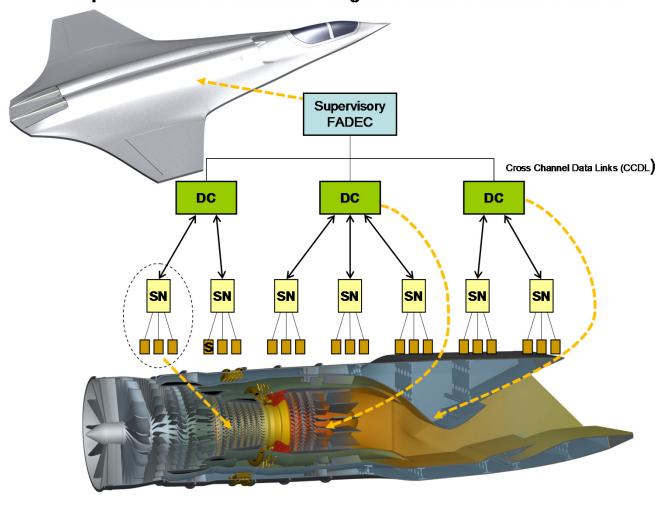
- Physical sensors shock, humidity, temperature, etc.
- Photonic-based chem/bio-sensors.
- Harsh Environment/High Temperature (1000-1400°C) MEMS packaging & sensors
 Systems integration (signal processing, logging, storage, communications)



Motivation

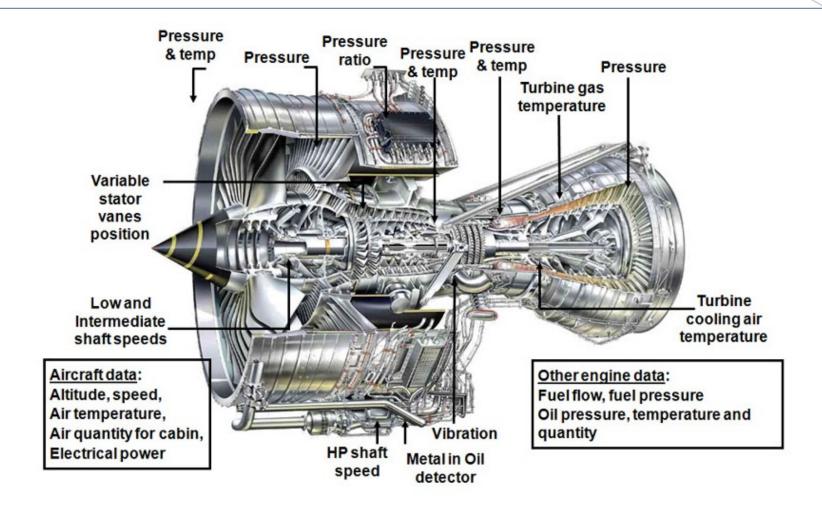


Implementation of Distributed Engine Controls with Smart Sensors



Motivation





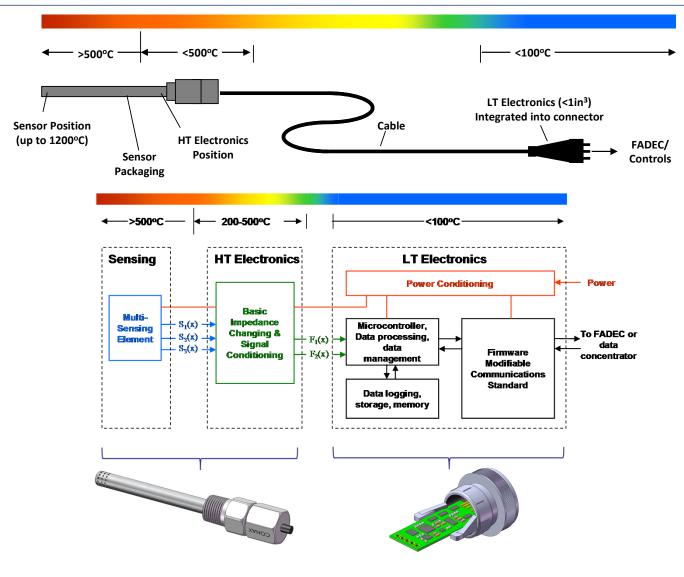
Motivation



- **Need/Challenge**: There is a growing demand for smart, hightemperature pressure sensors, signal conditioning electronics, and packaging in extreme environments providing information on engine conditions at the harshest environments.
 - Able to communicate over a data bus to FADEC/controller support distributed engine control
 - Compressor discharge pressures (0 to 700 psi) and temperatures (800°C- 1000°C) +/- .75% or +/- 0.5 psi accuracy
 - Reduced size and weight
 - Smart sensor features conditioned output, BIT status indicators, digital interface
 - Portions of electronics and packaging at elevated temperatures
- Approach: Leverage Sporian's previously developed and demonstrated high temperature pressure sensor technology and advance the sensor electronics and packaging into a "smart" form suitable for engine control applications/use.

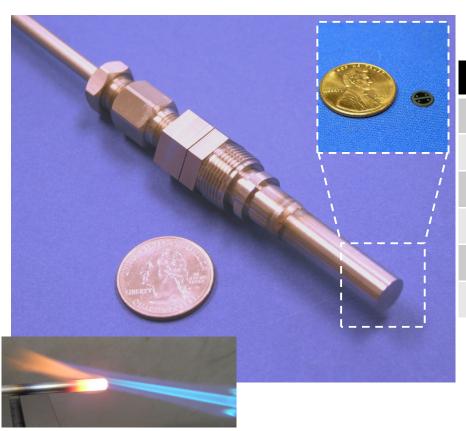
Smart Pressure Sensor Concept





Analog Pressure Sensor





Characteristic	Performance
Pressure Range (psi)	Atm-1000
Operation Temperature (C)	RT-1350
Frequency (khz)	1
Length (in.)	2-10
Diameter (in)	≥.25
Sensitivity/Combined Uncertainties	≤ 1% FS

High Temperature Electronics



Component Supplier	Passives	ICs	ASIC	Temp Range (°C)
Arkansas Power Electronics	X	Χ		<300
CISSIOD	Χ	Χ		<300
Cree	Χ	X		300–500
Honeywell	Χ	Χ	X	<300
Orbital Electronics	Χ	X	X	<300
Riedon	Χ			<400
TRS Technologies	Χ			<450
Vanguard Electronics	Χ			<250
Vectron International	Χ			250–300
xREL Semiconductor	Χ			230–300

High Temperature, Conformal Packaging



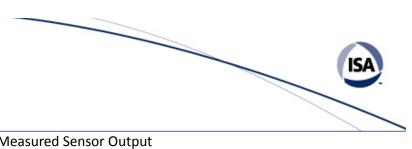


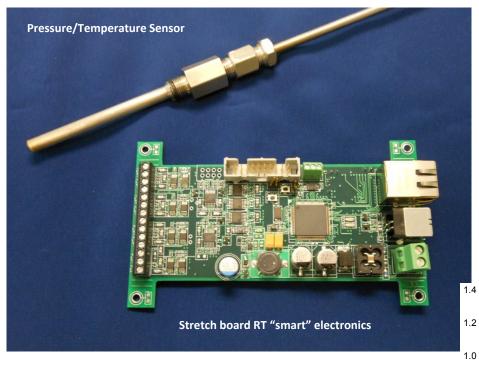
High Temperature, Conformal Packaging

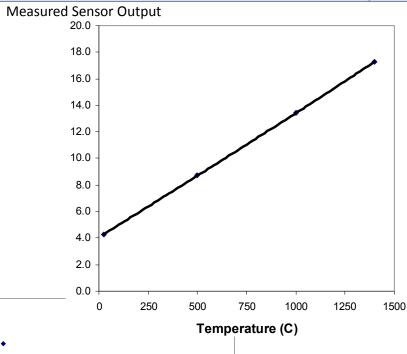


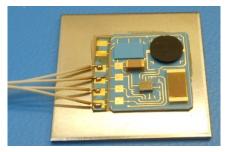
Test Item	Temp.	Duration	Results
Substrate materials	600 °C	100hr, multi-cycle	No degradation on flexural strength Dimensionally stabile
Substrate materials	850 °C	Single sweep	Low dielectric dissipation under 500°C
Conformal gold metallization	600 °C	100hr, multi-cycle	Reliable electrical continuity Stable adhesion to substrate
Conformal platinum metallization	600 °C	100hr, multi-cycle	Reliable electrical continuity Stable adhesion to substrate
Multilayer conformal substrate	600 °C	100hr, multi-cycle	Good geometrical and dimensional stability
Multilayer gold metallization	600 °C	100hr, multi-cycle	Reliable electrical continuity Stable adhesion to substrate
Multilayer platinum metallization	600 °C	100hr, multi-cycle	Reliable electrical continuity Stable adhesion to substrate
Die attach cements	1000°C	>20hr, Multi-cycle	Shear strength can survive 56 kG
Die attach	600 °C	100hr, multi-cycle	No degradation on shear strength
Au wire and flip chip bonding on Au metallization	600 °C	100hr, multi-cycle	Reliable electrical continuity Limited deformation/softening
Au wire bonding on Pt metallization	600 °C	100hr, multi-cycle	Reliable electrical continuity Limited deformation/softening
Au flip-chip bonding on Pt metallization	600 °C	100hr, multi-cycle	Reliable electrical continuity Reliable mechanical attachment
Potting cements	1000°C	>20hr, multi-cycle	No degradation on performances
Potting cements	600°C	100hr, multi-cycle	Shear strength can survive 56 kG
Potting glazes	600 °C	100hr, multi-cycle	No degradation on materials
Prototype w/ coating	600 °C	100hr, Multi-cycle	Reliable electrical continuity
Installation: Cements/Au-Paste	600 °C	100hr, multi-cycle	Shear strength can survive 56 kG
Installation: Brazing	600 °C	100hr, multi-cycle	Shear strength can survive 56 kG
Complete prototypes	Coup Coupl	oled 600 °C and 1000G led 300 °C and 13000G	Packaging and installation survived Reliable electrical continuity

Results to Date

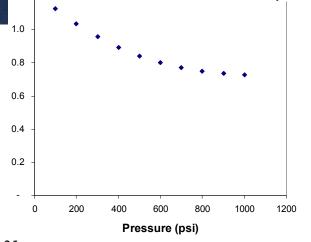








High Temperature electronics



25